



192520US2

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

**Match and Return**

IN RE APPLICATION OF:

Hayashi OTSUKI, et al.

SERIAL NO: 09/594,479

FILED: JUNE 14, 2000

FOR: PARTICLE-MEASURING  
SYSTEM AND PARTICLE-  
MEASURING METHOD

: GROUP ART UNIT: 2877

: DATE ALLOWED: August 13, 2002

: EXAMINER: PUNNOOSE, R.

PETITION UNDER 37 C.F.R. § 1.181

ASSISTANT COMMISSIONER FOR PATENTS  
WASHINGTON, D.C. 20231

SIR:

Applicants respectfully request invocation of the Commissioner's supervisory authority to require the Examiner to enter the attached Amendment under 37 C.F.R. § 1.312.

Applicants believe that no fees are necessary for this petition. However, in the event that fees are necessary, please charge Deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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